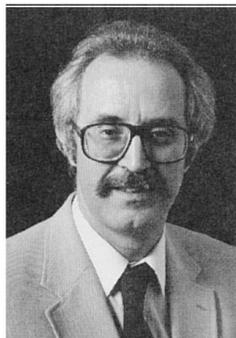


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## EDITORIAL



**Edward R. Dougherty**  
Editor

Papers given at the recent Electronic Imaging (EI) Symposium in San Jose, California, span all aspects of electronic imaging and by the nature of the symposium are topically relevant to JEI. To facilitate more interaction between the symposium and the journal, conference chairs at this year's symposium have been asked to identify several presentations that they believe are ready for publication in an archival journal. I have written each of the identified authors and suggested that they submit their paper to JEI. There can be no doubt that there were many more excellent papers presented in San Jose. Conference chairs are often busy making certain the conference runs successfully and therefore see only some fraction of the presentations. Moreover, I have asked them to keep the number of recommended papers small. Hence, I am taking this opportunity to encourage authors of symposium papers to consider submission of full-length journal papers to JEI upon completion of their research.

Based on the positive response of authors whose papers have been identified, we are asking conference chairs to again make recommendations during the 1997 EI symposium. The symposium and the journal are joint efforts of SPIE and IS&T, and represent the commitment of both societies to electronic imaging.

Besides the EI symposium, both SPIE and IS&T hold other conferences at which there are papers pertaining to

electronic imaging. In particular, I attended the SPIE Aerosense Symposium in Orlando, during which many papers topically suitable to JEI were presented. Our joint efforts with the EI symposium are not meant to imply that we are focused only on that symposium. We welcome contributions from all presenters. Given all the work that goes into the research and preparation behind a conference paper, where appropriate, the incremental effort required to prepare a journal paper is not that great.

As for JEI itself, we are quite happy with its current state. Not only are we looking forward to a number of outstanding special sections edited by leaders in their fields, this year we are also receiving an increasing number of submissions. And, based on comments I receive from the associate editors, these submissions are of increasing quality and represent the broad range of electronic imaging, both theoretical and applied.

On another note, I would like to point out an omission in the January 1996 issue. Proper recognition was not given to the guest editors of the special section on digital document imaging in that issue. We regret this oversight and thank the guest editors, Robert Loce, Robert Haralick, and Luc Vincent, for their excellent contributions. We are including in this issue their guest editorial for the digital document imaging special section, which appears on the next page.